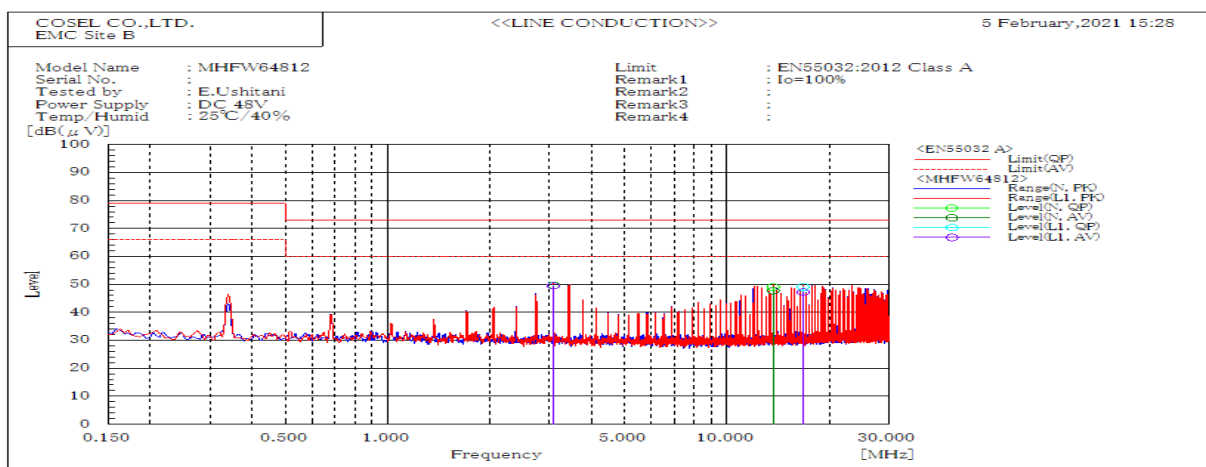
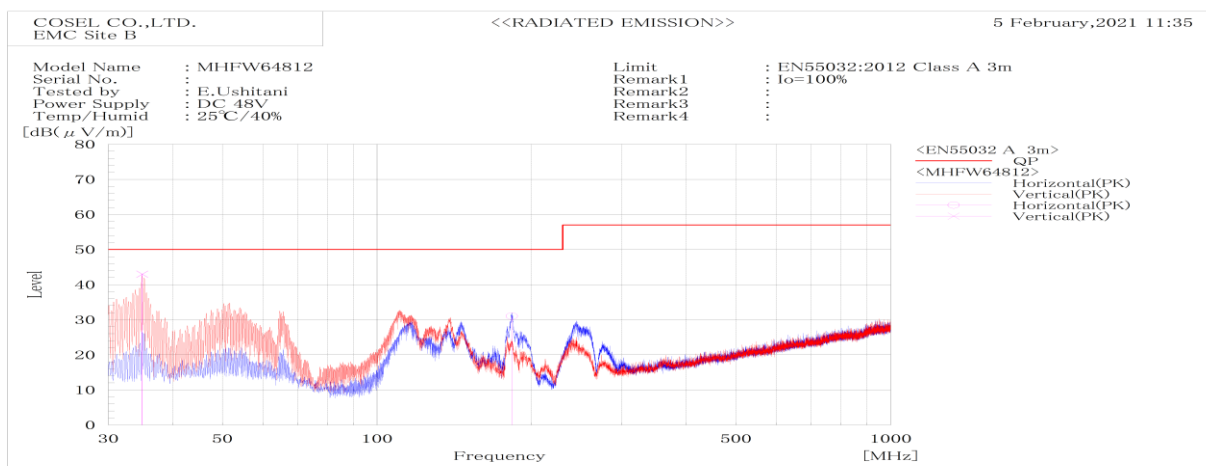


## DATA SHEET

Model	MHFW64812	Date	05-Nov-21
Test	EMI	Temp.	25 degreeC
	Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



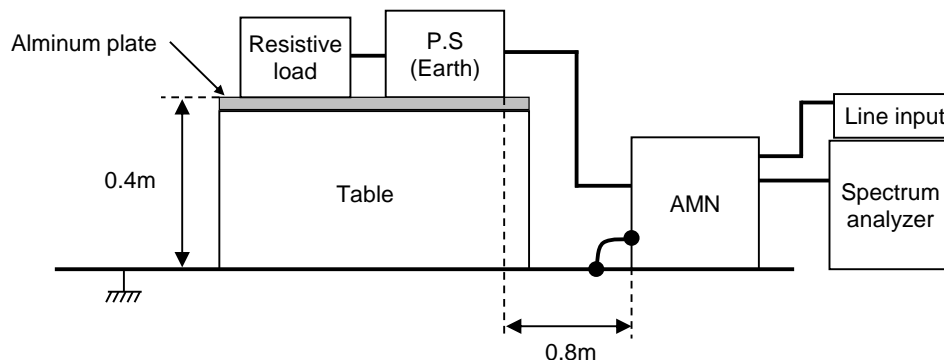
Frequency MHz	Line	Level dB(μV)	Limit dB(μV)	Margin dB	Pass/Fail	Remark
		QP	AV	QP	AV	
13.688	N	49.1	47.8	73	60	23.9 12.2 Pass
3.08	N	49.7	49.6	73	60	23.3 10.4 Pass
16.765	L1	49.1	47.2	73	60	23.9 12.8 Pass
3.079	L1	49.6	49.5	73	60	23.4 10.5 Pass



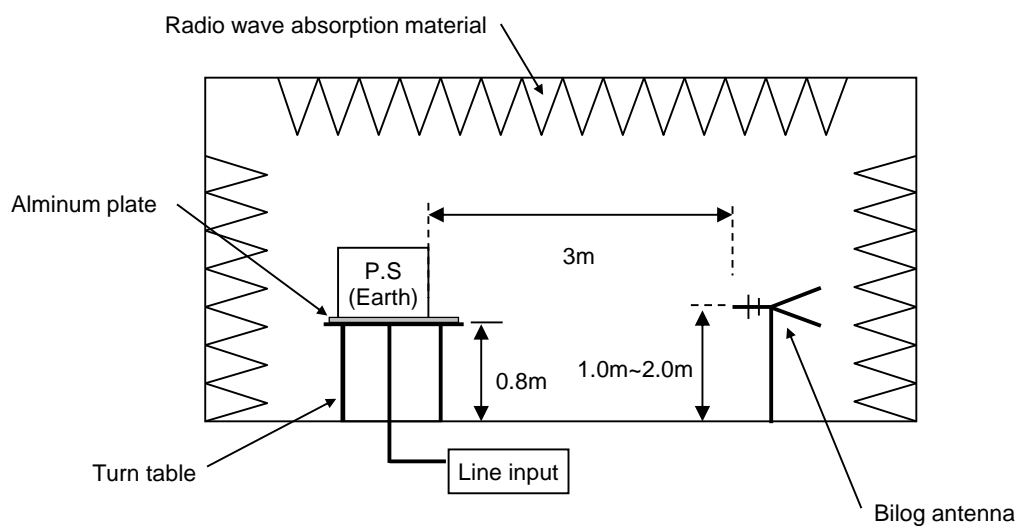
Frequency MHz	Polarization	Stability	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
182.917	H	Stable	31	50	19	Pass	198.4	351.4	
34.922	V	Stable	42.9	50	7.1	Pass	100.2	258.6	
34.926	V	Stable	43	50	7	Pass	100.4	216.9	

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

## 1. Line conduction



## 2. Radiated emission



## Conditions

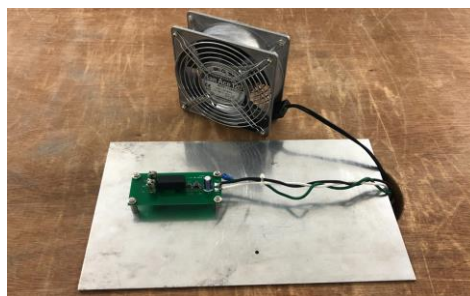
Test : EMI  
Model Name: MHFW6□□

## ○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



## ○Testing circuitry

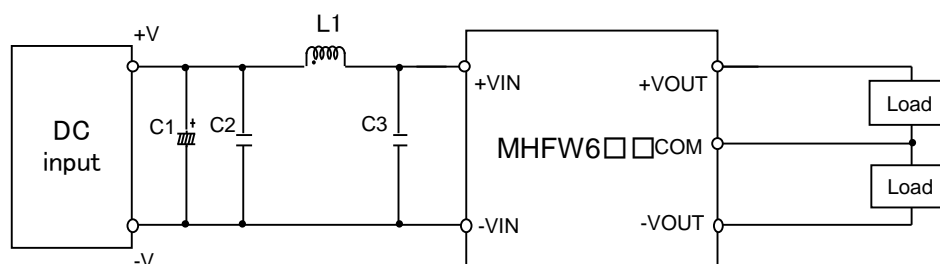


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 $\mu$ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	-
	MHFS648□□	-
C2 :	MHFS612□□	25V 10 $\mu$ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 $\mu$ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 $\mu$ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 $\mu$ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 $\mu$ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 $\mu$ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 $\mu$ H Inductor (LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 $\mu$ H Inductor (LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 $\mu$ H Inductor (LQH5BPN220MT0 MURATA MANUFACTURING)